

<b>Notice of References Cited</b>	Application/Control No. 09/683,677		Applicant(s)/Patent Under Reexamination DEVINS ET AL.	
	Examiner Saif A. Alhija		Art Unit 2128	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,279,146	08-2001	Evans et al.	716/18
*	B	US-5,600,579	02-1997	Steinmetz, Jr., William C.	703/13
*	C	US-5,805,605	09-1998	Lee et al.	714/718
*	D	US-6,498,999	12-2002	Reise, Brian G.	702/120
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	"An Embedded PowerPC SOC for Test and Measurement Applications", 2000 IEEE, Blaner et al.
*	V	Dutta et al. "Viper". September-October 2001. IEEE.
*	W	"System and Method Relating to Verification of Integrated Circuit Design" W00201424 , 06/2001
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.